



TPS53632G D-CAP+™ Half-Bridge PWM Controller

Optimized for GaN-based 48-V DC/DC Converter with I²C Interface

1 Features

- Valley Current Mode with Constant ON Time Control
- Lossless Current Sensing Scheme
- I²C Interface for VID Control and Telemetry
- Programmable I²C Addresses up to Eight Devices
- Switching Frequency up to 1 MHz
- Digital Current Monitor
- 7-Bit, DAC Output Range: 0.50-V to 1.52-V with 10-mV Step
- Accurate, Adjustable Voltage Positioning or Zero Slope Load-Line
- Selectable, 8-Level Current Limit
- Adjustable Output Slew Rate Control
- Default Boot Voltage: 1.00 V
- Small, 4-mm × 4-mm, 32-Pin, VQFN, PowerPAD Package

2 Applications

- 48-V Point-of-Load (POL) for Data Center and Telecommunication
- Wide Input Range Power Supplies for Industrial

3 Description

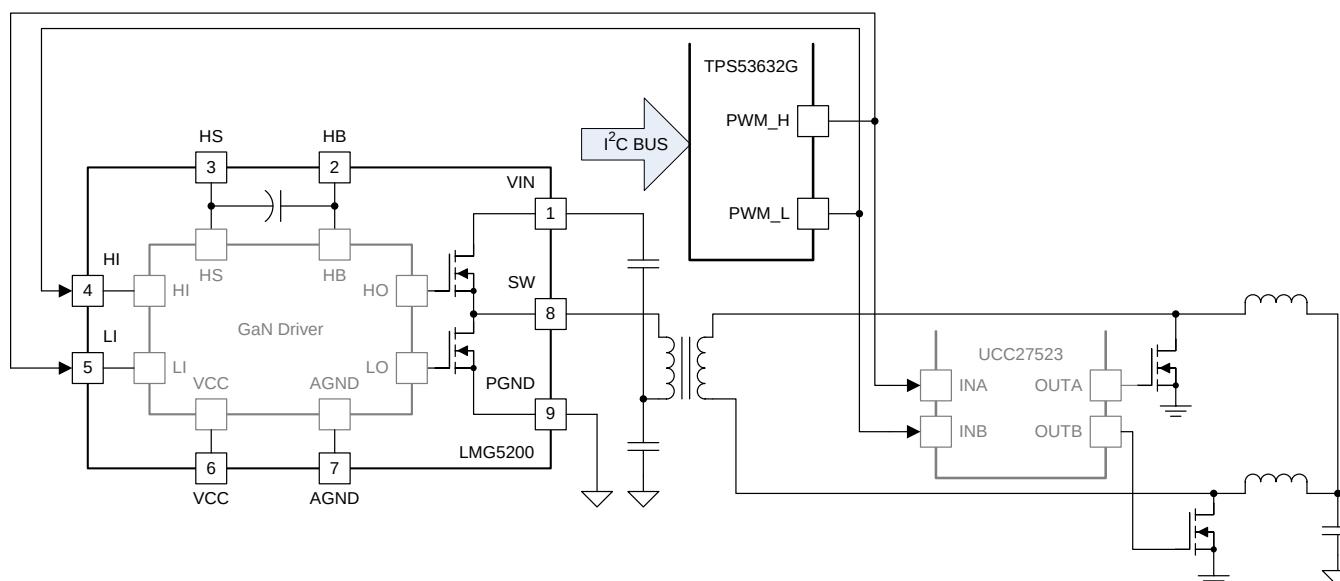
The TPS53632G device is a half-bridge PWM controller with D-CAP+™ architecture that provides fast transient response, lowest output capacitance and high efficiency in single stage conversion directly from 48-V bus. The TPS53632G device supports the standard I²C Rev 3.0 interface for dynamic control of the output voltage and current monitor telemetry. Paired with TI GaN power stages and drivers, the TPS53632G can switch up to 1 MHz to minimize magnetic component size and reduce overall board space. The LMG5200 GaN power stage is designed specifically for this controller to achieve high frequency and efficiency as high as 92% with 48-V to 1-V conversion.

Other features include adjustable control of output slew rate and voltage positioning. In addition, the TPS53632G device can be used along with other TI discrete power MOSFETs and drivers for silicon-based half bridge solutions. The TPS53632G device is packaged in a space saving, thermally enhanced, 32-pin VQFN package and is rated to operate at a range between –10°C and 105°C.

Device Information

PART NUMBER	PACKAGE	BODY SIZE
TPS53632G	VQFN	4 mm × 4 mm

Simplified Schematic



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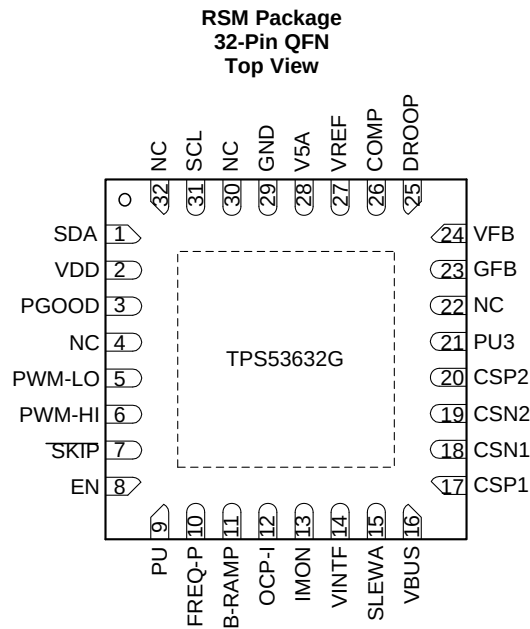
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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Original (April 2016) to Revision A	Page
• Updated document status from <i>Product Preview</i> to <i>Production Data</i>	1

5 Pin Configuration and Functions



Pin Functions

PIN		I/O	DESCRIPTION
NAME	NO.		
COMP	26	I	Error amplifier summing node. Resistors between the VREF pin and the COMP pin (R_{COMP}) and between the COMP pin and the DROOP pin (R_{DROOP}) set the droop gain.
CSP1	17	I	Positive current sense inputs. Connect to the most positive node of current sense resistor or inductor DCR sense network. Tie CSP2 or CSP1 (in that order) to a 3.3-V supply to disable the phase.
CSP2	20		
PU3	21		Connect to 3.3-V supply.
CSN1	18	I	Negative current sense inputs. Connect to the most negative node of current sense resistor or inductor DCR sense network. CSN1 has a secondary OVP comparator and includes the soft-stop, pull-down transistor.
CSN2	19		
NC	22	–	No connect.
DROOP	25	O	Error amplifier output. A resistor pair between this pin and the VREF pin and between the COMP pin and this pin sets the droop gain. $A_{DROOP} = 1 + R_{DROOP} / R_{COMP}$.
EN	8	I	Enable. 100-ns de-bounce. Regulator enters low-power mode, but retains start-up settings when brought low.
FREQ-P	10	I	A resistor between this pin and GND sets the per-phase switching frequency. Add a resistor to VREF to disable dynamic phase add and drop operation.
GFB	23	I	Voltage sense return. Tie to GND on PCB with a 10- Ω resistor to provide feedback when the microprocessor is not populated.
GND	29	–	Analog circuit reference. Tie this pin to a quiet point on the ground plane.
IMON	13	O	Analog current monitor output. $V_{IMON} = \Sigma V_{ISENSE} \times (1 + R_{IMON}/R_{OCP})$.
OCP-I	12	I/O	Voltage divider to IMON. Resistor ratio sets the IMON gain (see IMON pin). A resistor between this pin and GND (R_{OCP}) selects 1 of 8 OCP levels (per phase, latched at start-up).
PU	9	I	Pull-up to VREF through 10-k Ω resistor.
PGOOD	3	O	Power good output. Open-drain.
PWM-HI	6	O	PWM controls for the external driver; 5-V logic level. Controller forces signal to the tri-state level when needed.
PWM-LO	5		
NC	4	–	No connect.
NC	30 32	–	No connect.

Pin Functions (continued)

PIN		I/O	DESCRIPTION
NAME	NO.		
RAMP	11	I	Voltage divider to VREF. A resistor to GND sets the ramp setting voltage. The RAMP setting can be used to override the factory ramp setting.
SCL	31	I	Serial digital clock line.
SDA	1	I/O	Serial digital I/O line.
$\overline{\text{SKIP}}$	7	O	When high, the driver enters FCCM mode; otherwise, the driver is in DCM mode. Driving the tri-state level on this pin puts the drivers into a low power sleep mode.
SLEWA	15	I	The voltage sets the 3 LSBs of the I ² C address. The resistance to GND selects 1 of 8 slew rates. The start-up slew rate (EN transitions high) is SLEWRATE/2. The ADDRESS and SLEWRATE values are latched at start-up.
VINTF	14	I	Input voltage to interface logic. Voltage level can be between 1.62 V and 3.5 V.
V5A	28	I	5-V power input for analog circuits; connect through resistor to 5-V plane and bypass to GND with ceramic capacitor with a value of at least 1 μ F.
VBUS	16	I	The VBUS pin provides input voltage information to the on-time circuits for both converters.
VDD	2	I	3.3-V digital power input. Bypass this pin to GND with a capacitor with a value of at least 1 μ F.
VFB	24	I	Voltage sense line. Tie directly to V _{OUT} sense point of processor. Tie to V _{OUT} on PCB with a 10- Ω resistor to provide feedback when the microprocessor is not populated. The resistance between VFB and GFB is > 1 M Ω .
VREF	27	O	1.7-V, 500- μ A reference. Bypass to GND with a 0.22- μ F ceramic capacitor.
PAD	GND	–	Thermal pad Tie to the ground plane with multiple vias.

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) ⁽¹⁾

		MIN	MAX	UNIT
Input voltage	V5A	–0.3	6.0	V
	VBUS	–0.3	30.0	
	VDD	–0.3	3.6	
	COMP, CSP1, CSP2, CSN1, CSN2, DROOP, EN, FREQ-P, IMON, OCP-I, O- USR, RAMP, SCL, SDA, SLEWA, VFB, VINTF, VREF	–0.3	3.6	
	GFB	–0.2	0.2	
Output voltage	PGOOD	–0.3	3.6	V
	PWM-LO, PWM-HI, SKIP	–0.3	6.0	
Operating junction temperature, T _J		–40	150	°C
Storage temperature, T _{stg}			150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM) ESD stress voltage ⁽¹⁾	±2000	V
		Charged device model (CDM) ESD stress voltage ⁽²⁾	±750	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V_I	Input voltage	V5A	4.5	5.5
		VBUS	–0.1	28
		VDD	3.1	3.5
		CSN1, CSN2, CSP1, CSP2, IMON, OCP-I, O-USR, RAMP, SCL, SDA, VFB, VINTF, VREF	–0.1	3.5
		COMP, DROOP, EN, FREQ-P, SLEWA	–0.1	5.5
		GFB	–0.1	0.1
V_O	Output voltage	PGOOD	–0.1	3.5
		PWM-LO, PWM-HI, SKIP	–0.1	5.5
T_A	Operating ambient temperature	–10	105	°C

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		TPS53632G	UNITS
		RSM (VQFN)	
		32 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	37.2	°C/W
$R_{\theta JCTop}$	Junction-to-case (top) thermal resistance	31.9	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	8.1	°C/W
$R_{\psi JT}$	Junction-to-top characterization parameter	0.4	°C/W
$R_{\psi JB}$	Junction-to-board characterization parameter	7.9	°C/W
$R_{\theta JCBot}$	Junction-to-case (bottom) thermal resistance	2.2	°C/W

- (1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report, [SPRA953](#).

6.5 Electrical Characteristics

over recommended free-air temperature range, $V_{V5A} = 5.0\text{ V}$, $V_{VDD} = 3.3\text{ V}$, $V_{GFB} = \text{GND}$, $V_{VFB} = V_{CORE}$ (unless otherwise noted)

PARAMETER		CONDITIONS	MIN	TYP	MAX	UNIT
POWER SUPPLY: CURRENTS, UVLO AND POWER-ON-RESET						
I _{V5-3P}	V5A supply current	V _{DAC} < V _{VFB} < (V _{DAC} + 100 mV), EN = 'HI'		3.6	6.0	mA
I _{VDD-3P}	VDD supply current	V _{DAC} < V _{VFB} < (V _{DAC} + 100 mV), EN = 'HI', digital buses idle		0.2	0.8	
I _{V5STBY}	V5A standby current	EN = 'LO'		125	200	μA
I _{VDDSTBY}	VDD standby current	EN = 'LO'		23	40	
I _{VDD-1P8}	VINTF supply current	All conditions, digital buses idle		1.7	5.0	V
V _{UVLOH}	V5A UVLO 'OK' threshold	V _{VFB} < 200 mV, Ramp up, V _{VDD} > 3 V, EN = 'HI', switching begins.	4.2	4.4	4.52	
V _{UVLOL}	V5A UVLO fault threshold	Ramp down, EN = 'HI', V _{VDD} > 3 V, V _{VFB} = 100 mV, restart if 5-V falls below V _{POR} then rises > V _{UVLOH} , or EN is toggled w/ V _{V5A} > V _{UVLOH}	4.00	4.2	4.35	
V _{POR}	V5A fault latch reset threshold	Ramp down, EN = 'HI', V _{VDD} > 3 V. Can restart if 5-V rises to V _{UVLOH} and no other faults present.	1.2	1.9	2.5	
V _{3UVLOH}	VDD UVLO 'OK' threshold	V _{VFB} < 200 mV. Ramp up, V _{V5A} > 4.5 V, EN = 'HI', Switching begins.	2.5	2.8	3.0	
V _{3UVLOL}	Fault threshold	Ramp down, EN = 'HI', V _{5A} > 4.5V, V _{FB} = 100 mV, restart if 5-V dips below V _{POR} then rises > V _{UVLOH} or EN is toggled with 5 V > V _{UVLOH}	2.4	2.6	2.8	
V _{POR}	VDD fault latch	Ramp down, EN = 'HI', V _{V5A} > 4.5 V, can restart if 5-V supply rises to V _{UVLOH} and no other faults present.	1.2	1.9	2.5	
V _{INTFUUVLOH}	VINTF UVLO OK	Ramp up, EN = 'HI', V _{V5A} > 4.5 V, V _{VFB} = 100 mV	1.4	1.5	1.6	
V _{INTFUUVLOL}	VINTF UVLO falling	Ramp down, EN = 'HI', V _{V5A} > 4.5 V, V _{VFB} = 100 mV	1.3	1.4	1.5	
REFERENCES: DAC, VREF, VFB DISCHARGE						
V _{VIDSTP}	VID step size	Change VID0 HI to LO to HI		10		mV
V _{DAC1}	VFB tolerance	No load active, 1.36 V ≤ V _{VFB} ≤ 1.52 V, I _{OUT} = 0 A	−9		9	
V _{DAC2}	VFB tolerance	No load medium, 1.0 V ≤ V _{VFB} ≤ 1.35 V, I _{OUT} = 0 A	−8		8	
		No load medium, 0.5 V ≤ V _{VFB} ≤ 0.99 V, I _{OUT} = 0 A	−7		7	
V _{VREF}	VREF output	VREF output 4.5 V ≤ V _{V5A} ≤ 5.5 V, I _{VREF} = 0 A	1.66	1.700	1.74	V
V _{VREFSRC}	VREF output source	0 A ≤ I _{REF} ≤ 500 μA, HP-2	−4	−3		mV
V _{VREFSNK}	VREF output sink	−500 A ≤ I _{REF} ≤ 0 A, HP-2		3	4	
V _{BOOT}	Internal VFB initial boot voltage	Initial DAC boot voltage	0.99	1.00	1.01	V
RAMP SETTINGS						
V _{RAMP}	Compensation ramp	R _{RAMP} = 30 kΩ		60		mV
		R _{RAMP} = 56 kΩ		120		
		R _{RAMP} = 100 kΩ		160		
		R _{RAMP} ≥ 150 kΩ		40		
VOLTAGE SENSE: VFB AND GFB						
R _{VFB}	VFB/GFB Input resistance	Not in fault, disable or UVLO, V _{VFB} = V _{DAC} = 1.5 V, V _{GFB} = 0 V, measure from VFB to GFB	1			MΩ
V _{DELGND}	GFB Differential	GND to GFB		±100		mV
CURRENT MONITOR						
V _{AL-ADC}	IMON ADC output	ΣΔCS = 0 mV, A _{IMON} = 3.867		00h		
		ΣΔCS = 1.5 mV, A _{IMON} = 3.867		19h		
		ΣΔCS = 7.5 mV, A _{IMON} = 3.867		80h		
		ΣΔCS = 15 mV, A _{IMON} = 3.867		FFh		
LR _{IMON}	IMON linear range	Each phase, CSPx – CSNx	50			mV

Electrical Characteristics (continued)

over recommended free-air temperature range, $V_{V5A} = 5.0\text{ V}$, $V_{VDD} = 3.3\text{ V}$, $V_{GFB} = \text{GND}$, $V_{VFB} = V_{CORE}$ (unless otherwise noted)

PARAMETER		CONDITIONS	MIN	TYP	MAX	UNIT
CURRENT SENSE: OVER CURRENT PROTECTION, PHASE ADD AND DROP, AND PHASE BALANCE						
V _{OCP}	OCP voltage (valley current limit)	R _{OCP-I} = 20 kΩ	3.7	7.6	11.4	mV
		R _{OCP-I} = 24 kΩ	6.6	10.5	14.1	
		R _{OCP-I} = 30 kΩ	10.6	14.5	18.0	
		R _{OCP-I} = 39 kΩ	15.4	19.5	23.0	
		R _{OCP-I} = 56 kΩ	21.3	25.4	29.0	
		R _{OCP-I} = 75 kΩ	28.4	32.5	36.2	
		R _{OCP-I} = 100 kΩ	36.3	40.5	44.0	
		R _{OCP-I} = 150 kΩ	45.0	49.3	53.0	
I _{CS}	CS pin input bias current	CSPx and CSNx	−500	0.2	500	nA
A _{V-EA}	Error amplifier total voltage gain ⁽¹⁾	VFB to DROOP	80			dB
I _{EA_SR}	Error amplifier source current	I _{DROOP} , V _{VFB} = V _{DAC} + 50 mV, R _{COMP} = 1 kΩ	1			mA
I _{EA_SK}	Error amplifier sink current	I _{DROOP} , V _{VFB} = V _{DAC} − 50mV, R _{COMP} = 1 kΩ	−1			
A _{CSINT}	Internal current sense gain	Gain from CSPx – CSNx to PWM comparator, R _{SKIP} = Open	5.8	6.0	6.2	V/V
R _{SFTSTP}	Soft-stop transistor resistance	Connected to CSN1		100	200	Ω
R _{VIN}	VIN resistance	EN = HI		350	600	kΩ
		EN = LOW or STBY	10			MΩ
PROTECTION: OVP, UVP, PGOOD AND THERMAL SHUTDOWN						
V _{OVPH}	Fixed OVP voltage	V _{CSN1} > V _{OVPH} for 1 μs	1.60	1.70	1.80	V
V _{PGDH}	PGOOD high threshold	Measured at the VFB pin w/r/t VID code, device latches OFF	190		245	mV
V _{PGDL}	PGOOD low threshold	Measured at the VFB pin w/r/t VID code, device latches OFF	-348		-280	
PWM AND SKIP OUTPUTS: I/O VOLTAGE AND CURRENT						
V _{P-S_L}	PWMx/SKIP - Low	PWM _{ILOAD} = ± 1 mA, SKIP _{ILOAD} = ± 100 μA		0.15	0.3	V
V _{P-S_H}	PWMx/SKIP - High	PWM _{ILOAD} = ± 1 mA, SKIP _{ILOAD} = ± 100 μA	4.2			
LOGIC INTERFACE: VOLTAGE AND CURRENT						
R _{VRTTL}	Pull-down resistance	V _{SDA} = 0.31	4		15	Ω
R _{VRPG}		V _{PGOOD} = 0.31		36	50	
I _{VRTTLK}	Logic leakage current	V _{SCL} = 1.8 V, V _{SDA} = 1.8 V, V _{PGOOD} = 3.3 V	-2	0.2	2	μA
V _{IL}	Low-level Input voltage	SCL, SDA; V _{VINTF} = 1.8 V			0.6	V
V _{IH}	High-level Input voltage		1.2			
I _{ENH}	I/O leakage, EN	Leakage current , V _{EN} = 1.8 V		24	40	μA

(1) Specified by design. Not production tested.

6.6 Timing Requirements

The TPS53632G requires the ENABLE signal on Pin 8 to go from low to high only after the V5A (5V), the VDD (3.3V) and the VIN rails have gone high.

6.7 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{OFF} (min)	Controller minimum OFF time	Fixed value	20			ns
t _{ON} (min)	Controller minimum ON time	R _{CF} = 150 kΩ, V _{VIN} = 20 V, V _{VFB} = 0 V	20			
TIMERS: SLEW RATE, ADDR, SLEEP EXIT, ON TIME AND I/O TIMING						
t _{START-CB}	Cold boot time ⁽¹⁾	V _{BOOT} > 0V , EN = high, C _{REF} = 0.33 μF			1.2	ms
t _{STBY-E}	Standby exit time ⁽²⁾	V _{VID} = 1.28 V, R _{SLEW} = 39 kΩ			250	μs
SL _{SET}	Slew rate setting for VID change	R _{SLEW} = 20 kΩ	6			mV/μs
		R _{SLEW} = 24 kΩ	12			
		R _{SLEW} = 30 kΩ	18			
		R _{SLEW} = 39 kΩ	24			
		R _{SLEW} = 56 kΩ	30			
SL _{START} ⁽³⁾	Slew rate setting for start-up	EN goes high, R _{SLEW} = 39 kΩ	12			mV/μs
ADDR	Address setting 3 LSB of I ² C address	V _{SLEWA} ≤ 0.30 V (Addr = 100 0xxx)		000b		
		0.75 V ≤ V _{SLEWA} ≤ 0.85 V		011b		
		1.15 V ≤ V _{SLEWA} ≤ 1.25 V		101b		
t _{PGDDGLTO}	PGOOD deglitch time (over) ⁽⁴⁾			1		μs
t _{PGDDGLTU}	PGOOD deglitch time (under) ⁽⁵⁾			31		
t _{ON}	On time	R _{CF} = 20 kΩ		295		ns
		R _{CF} = 24 kΩ, V _{VIN} = 12 V, V _{VFB} = 1 V, f _{SW} = 400 kHz		230		
		R _{CF} = 39 kΩ, V _{VIN} = 12 V, V _{VFB} = 1 V, f _{SW} = 600 kHz		164		
		R _{CF} = 75 kΩ, V _{VIN} = 12 V, V _{VFB} = 1 V, f _{SW} = 800 kHz		140		
		R _{CF} = 150 kΩ, V _{VIN} = 12 V, V _{VFB} = 1 V, f _{SW} = 1 MHz		128		
PWM AND SKIP OUTPUTS						
t _{P-S_H-L} ⁽³⁾	PWMx/SKIP H-L transition time	10% to 90%, both edges		7	20	ns
PROTECTION: OVP, UVP, PGOOD AND THERMAL SHUTDOWN						
t _{PG2}	PGOOD low	Low state time after EN goes low.	225	250	275	μs

(1) Cold boot time is defined as the time from UVLO detection to V_{OUT} ramp.

(2) Standby exit time is defined as the time from EN assertion until PGOOD goes high

(3) Specified by design. Not production tested.

(4) PGOOD deglitch time (over) is defined as the time from when the VFB pin rises above the 250-mV V_{DAC} boundary to when the PGOOD pin goes low.

(5) PGOOD deglitch time (under) is defined as the time from when the VFB pin falls below the -300-mV V_{DAC} boundary to when the PGOOD pin goes low.

6.8 Typical Characteristics (Half-Bridge Operation)

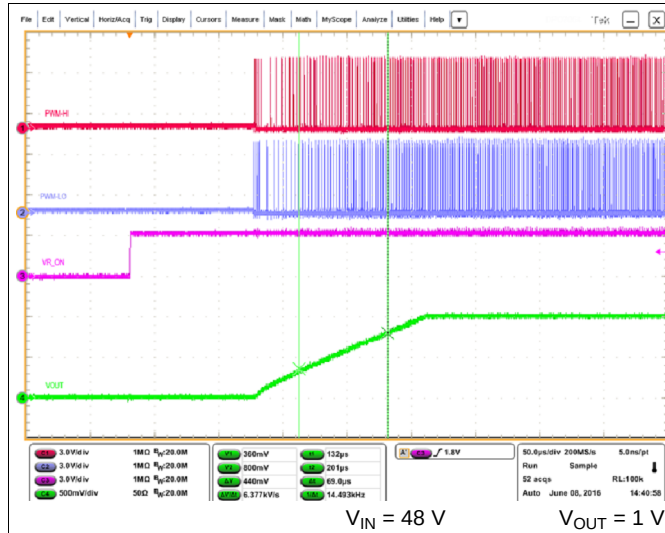


Figure 1. Startup

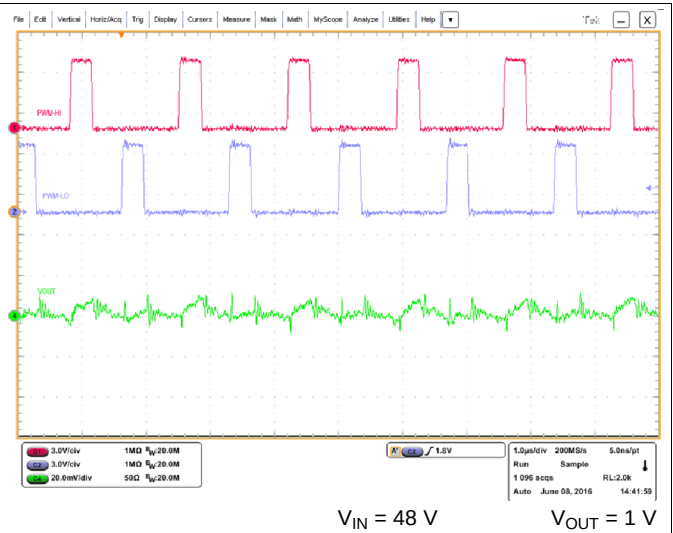


Figure 2. Switching Waveform

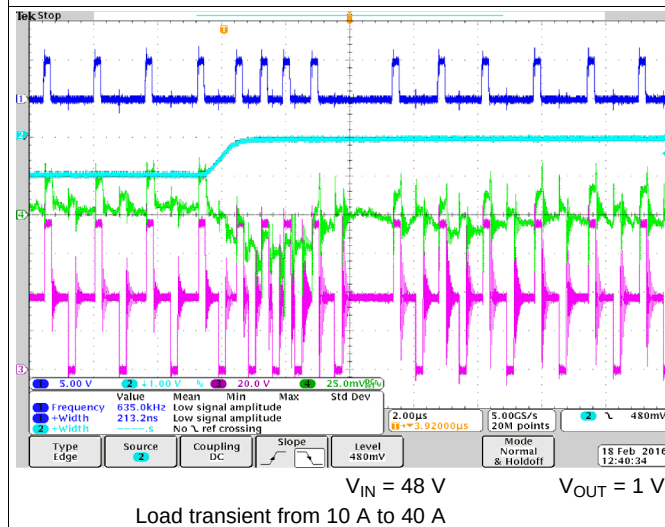


Figure 3. Load Transient

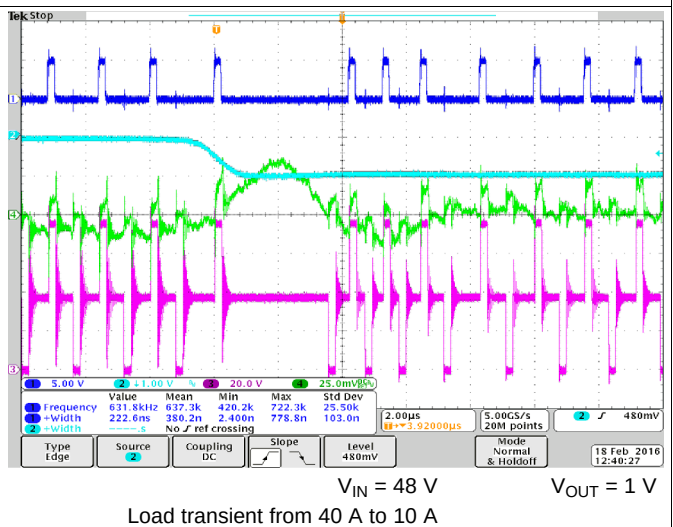


Figure 4. Load Transient

7 Detailed Description

7.1 Overview

The TPS53632G device is a DCAP+ mode half-bridge PWM controller optimized for high frequency operation using GaN switchers. The DAC outputs a reference in accordance with the 7-bit VID code as defined in [Table 1](#). This DAC sets the output voltage.

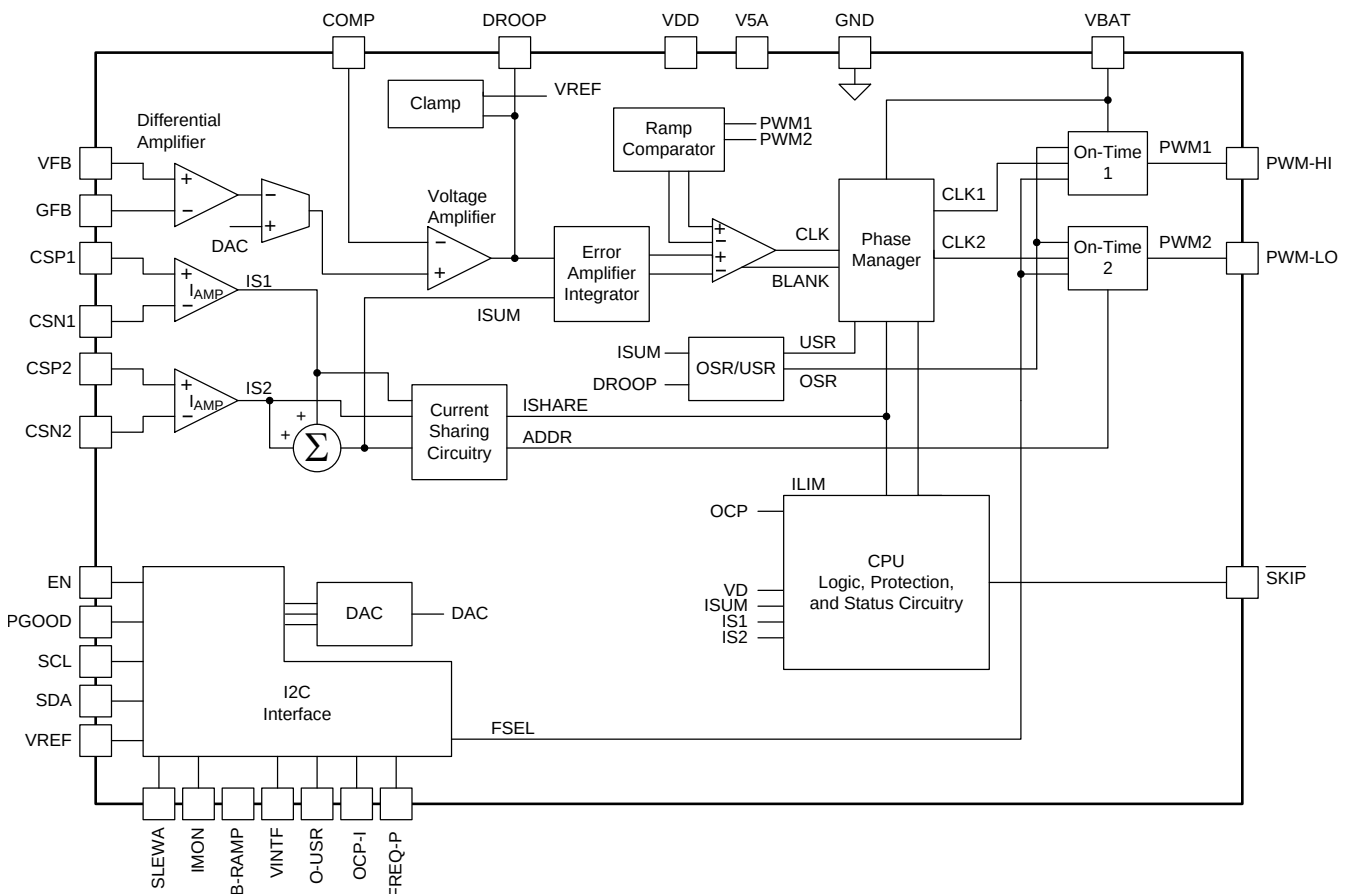
In adaptive on-time converters, the controller varies the on-time as a function of input and output voltage to maintain a nearly constant frequency during steady-state conditions. With conventional voltage-mode constant on-time converters, each cycle begins when the output voltage crosses to a fixed reference level. However, in the TPS53632G device, the cycle begins when the current feedback reaches an error voltage level which corresponds to the amplified difference between the DAC voltage and the feedback output voltage. In the case of half bridge operation, the device sums the current feedback from secondary current and doubles the output of the internal current-sense amplifiers.

This approach has two advantages:

- The amplifier DC gain sets an accurate linear load-line slope, which is required for certain V_{CORE} applications.
- The device filters the error voltage input to the PWM comparator to improve the noise performance.

During a steady-state condition, the phases of the TPS53632G switch are 180° phase-displacement. The phase displacement is maintained both by the architecture (which does not allow the high-side gate drive outputs of more than one phase to be ON in any condition except transients) and the current ripple (which forces the pulses to be spaced equally). The controller forces current-sharing by adjusting the ON-time of each phase. Current balancing requires no user intervention, compensation, or extra components.

7.2 Functional Block Diagram



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7.3 Feature Description

7.3.1 Current Sensing

The TPS53632G device provides independent channels of current feedback for secondary side current doublers. These independent channels increase the system accuracy and reduce the dependence of circuit performance on layout compared to an externally summed architecture. The design can use *inductor DCR sensing* to yield the best efficiency or *resistor current sensing* to yield the most accuracy across wide temperature ranges. DCR sensing can be optimized by using a NTC thermistor to reduce the variation of current sense with temperature.

The pins CSP1, CSN1, CSP2 and CSN2 are the current sensing pins.

7.3.2 Load Transients

When the load increases suddenly, the output voltage immediately drops. This voltage drop is reflected as a rising voltage on the DROOP pin. This rising voltage forces the PWM to pulse sooner and more frequently which causes the inductor current to rapidly increase. As the inductor current reaches the new load current, a steady-state operating condition is reached and the PWM switching resumes the steady-state frequency. Similarly, when the load releases suddenly, the output voltage rises. This rise is reflected as a falling voltage on the COMP pin. This rising voltage forces a delay in the PWM pulses until the inductor current reaches the new load current, when the switching resumes and steady-state switching continues.

7.3.3 PWM and SKIP Signals

The PWM and SKIP signals are outputs of the controller and serve as input to the driver or DrMOS type devices. Both are 5-V logic signals. The PWM signals are logic high when the high-side driver turns ON. The PWM signal must be low for the low-side drive to turn ON. When both the drive signals are OFF, the PWM is in tri-state.

7.3.4 5-V, 3.3-V and 1.8-V Undervoltage Lockout (UVLO)

The TPS53632G device continuously monitors the voltage on the V5A, VDD and VINTF pins to ensure a value high enough to bias the device properly and provide sufficient gate drive potential to maintain high efficiency. The converter starts with a voltage of approximately 4.4 V and has a nominal 200 mV of hysteresis. After the 5VA, VDD or VINTF pins go below the V_{UVLOL} level, the corresponding voltage must fall below V_{POR} (1.5 V) to reset the device.

The input voltage (V_{VIN}) does not include a UVLO function, so the circuit runs with power inputs as low as approximately $3 \times V_{OUT}$.

7.3.5 Output Undervoltage Protection (UVP)

Output undervoltage protection works in conjunction with the current protection described in the [Overcurrent Protection \(OCP\)](#) section. If the output voltage drops below the low PGOOD voltage threshold, then the drivers are turned OFF until the EN pin power is cycled.

7.3.6 Overcurrent Protection (OCP)

The TPS53632G device uses a valley current limiting scheme, so the ripple current must be considered. The DC current value at OCP (I_{OCP}) is the OCP limit value plus half of the ripple current. Current limiting occurs on a phase-by-phase and pulse-by-pulse basis. If the voltage between the CSPx and CSNx pins is above the OCP value, the converter delays the next ON pulse until that voltage difference drops below the OCP limit. For inductor current sensing circuits, the voltage between the CSPx and CSNx pins is the inductor DCR value multiplied by the resistor divider which is part of the NTC compensation network. As a result, a wide range of OCP values can be obtained by changing the resistor divider value. In general, use the highest OCP setting possible with the least attenuation in the resistor divider to provide as much signal to the device as possible. This provides the best performance for all parameters related to current feedback.

In OCP mode, the voltage drops until the UVP limit is reached. Then the converter sets the PGOOD to inactive, and the drivers are turned OFF. The converter remains in this state until the device is reset by the V5A, VDD or VINTF rails.

Feature Description (continued)

7.3.7 Overvoltage Protection

An OVP condition is detected when the output voltage is greater than the PGDH voltage, and greater than V_{DAC} . $V_{OUT} > +V_{PGDH}$ greater than V_{DAC} . In this case, the converter sets PGOOD inactive, and turns ON the drive for the low-side MOSFET. The converter remains in this state until the device is reset by cycling the V5A, VDD or VINTF pin. However, the OVP threshold is *blanked* much of the time. In order to provide protection to the processor 100% of the time, there is a second OVP level fixed at V_{OVPH} which is always active. If the fixed OVP condition is detected, the PGOOD are forced inactive and the low-side MOSFETs are turned ON. The converter remains in this state until the V5A, VDD or VINTF pin is reset.

7.3.8 Analog Current Monitor, IMON and Corresponding Digital Output Current

The TPS53632G device includes a current monitor function. The current monitor supplies an analog voltage, proportional to the load current, on the IMON pin.

The current monitor function is related to the OCP selection resistors. The R_{OCP} is the resistor between the OCP-I pin and GND and R_{CIMON} is the resistor between the IMON pin to the OCP-I pin that sets the current monitor gain. Equation 1 shows the calculation for the current monitor gain.

$$V_{IMON} = 10 \times 1 + \frac{(R_{IMON})}{(R_{OCP})} \times \sum V_{CSn} \xrightarrow{\text{yields}} V$$

where

- $\sum V_{CS}$ is the sum of the DC voltages at the inputs to the current sense amplifiers (1)

To ensure stable current monitor operation and at the same time provide a fast dynamic response, connect a capacitor with a value between 4.7-nF and 10-nF between the IMON pin and GND.

Set the analog current monitor so that at the maximum processor current ($I_{CC(max)}$) level, the IMON voltage is 1.7 V. This corresponds to a digital output current value of 'FF' in register 03H.

7.3.9 Addressing

The TPS53632G device can be configured for three different base addresses by setting a voltage on the SLEWA pin. Configure a resistor divider on SLEWA from VREF to GND. A resistor between the SLEWA pin and GND sets the slew rate. Once the slew rate resistor is selected, the resistor from the VREF pin to the SLEWA pin can be chosen based on the required base address. For a base address of 0, the VREF to SLEWA resistor can be left open.

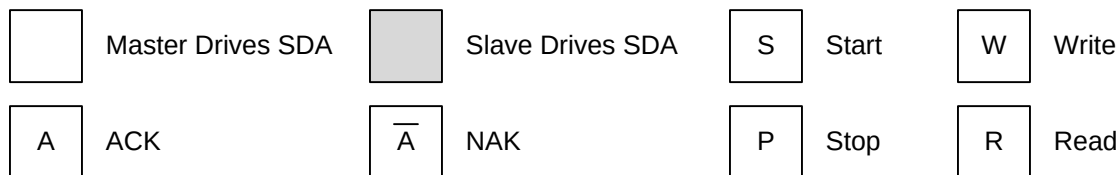
7.3.10 I²C Interface Operation

The TPS53632G device includes a slave I²C interface accessed via the SCL (serial clock) and SDA (serial data) pins. The interface sets the base VID value, receives current monitor telemetry, and controls functions described in this section. It operates when EN = low, with the bias supplies in regulation. It is compliant with I²C specification UM10204, Revision 3.0. The characteristics are:

- Addressing
 - 7-bit addressing; address range is 100 0xxx (binary)
 - Last three bits are determined by the SLEWA pin at start-up
- Byte read / byte write protocols only (See figures in [Protocol Examples](#) section)
- Frequency
 - 100 kHz
 - 400 kHz
 - 1 MHz
 - 3.4 MHz
- Logic inputs are 1.8-V logic levels (3.3-V tolerant)

Feature Description (continued)

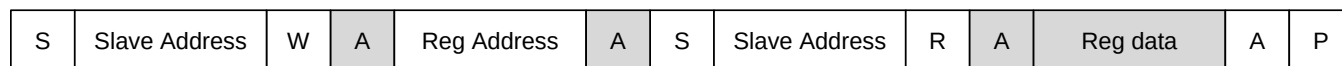
7.3.10.1 Key for Protocol Examples



UDG-13045

7.3.10.2 Protocol Examples

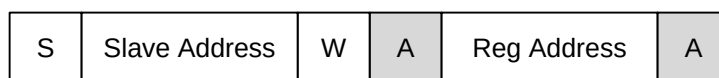
The good byte read transaction the controller ACKs and the master terminates with a NAK/stop.



UDG-13046

Figure 5. Good Byte Read Transaction

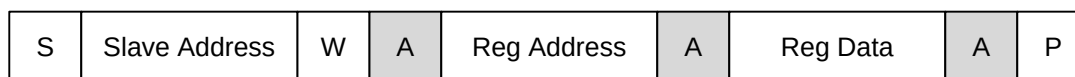
The controller issues a NAK to the read command with an invalid register address.



UDG-13047

Figure 6. NAK Invalid Register Address

Figure 7 illustrates a good byte write.



UDG-13048

Figure 7. Good Byte Write

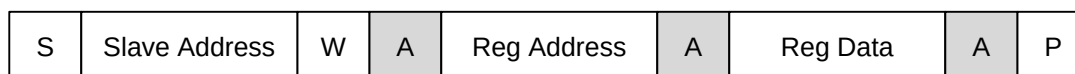
The controller issues a NAK to a write command with an invalid register address.



UDG-13049

Figure 8. Invalid NAK Register Address

The controller issues a NAK to a write command for the condition of invalid data.

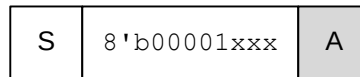


UDG-13050

Figure 9. Invalid NAK Register Data

The device executes the master code sequence shown in Figure 10 to enter Hs (3.4-MHz SCL) mode.

Feature Description (continued)



UDG-13051

Figure 10. Master Code Sequence

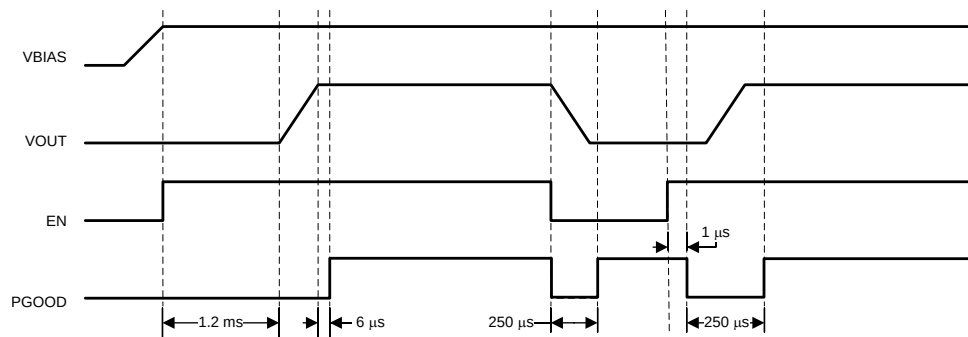
7.3.11 Start-Up Sequence

The TPS53632G initializes when all of the supply voltages rise above the UVLO thresholds. This function is also known as a *cold boot*. The device then reads all of the various settings (such as frequency and overcurrent protection). This process takes less than 1.2 ms. During this time, the VSR pin initializes to the BOOT voltage. The output voltage rises to the voltage select register (VSR) level when the EN pin (enable) goes high. As soon as the BOOT sequence completes, PGOOD is HIGH and the I²C interface can be used to change the voltage select register. The current VSR value is held when EN goes low and returns to a high state. This function is also known as a *warm boot*. The VSR can be changed when EN is low, however, this is not recommended prior to completion of the cold boot process.

7.3.12 Power Good Operation

PGOOD is an open-drain output pin that is designed to be pulled up with an external resistor to a voltage 3.6 V or less. Normal PGOOD operation (exclusive of OC or MAXVID interrupt action) is shown in Figure 11. On initial power-up, a power good status occurs within 6 μ s of the DAC reaching its target value. When EN is brought low, the PGOOD pin is also brought low for 250 μ s and then is allowed to float. The TPS53632G device pulls down the PGOOD signal when the EN signal subsequently goes high and returns high again within 6 μ s of the end of the DAC ramp. The delay period between the EN pin going high and the PGOOD pin going low in this case is less than 1 μ s.

Figure 11 shows the power good operation at initial start up and with falling and rising EN.



UDG-13096

Figure 11. Power Good Operation

Feature Description (continued)

7.3.13 Fault Behavior

The TPS53632G device has a complete suite of fault detection and protection functions, including input undervoltage lockout (UVLO) on all power inputs, overvoltage and overcurrent limiting and output undervoltage detection. The protection limits are summarized in [Table 1](#). The converter suspends switching when the limits are exceeded and the PGOOD pin goes low. In this state, the fault register 14h is readable. To exit fault protection mode, power must be cycled.

Table 1. TPS53632G VID Table

VID6	VID5	VID4	VID3	VID2	VID1	VID0	HEX	VOLTAGE
0	0	1	1	0	0	1	19	0.5000
0	0	1	1	0	1	0	1A	0.5100
0	0	1	1	0	1	1	1B	0.5200
0	0	1	1	1	0	0	1C	0.5300
0	0	1	1	1	0	1	1D	0.5400
0	0	1	1	1	1	0	1E	0.5500
0	0	1	1	1	1	1	1F	0.5600
0	1	0	0	0	0	0	20	0.5700
0	1	0	0	0	0	1	21	0.5800
0	1	0	0	0	1	0	22	0.5900
0	1	0	0	0	1	1	23	0.6000
0	1	0	0	1	0	0	24	0.6100
0	1	0	0	1	0	1	25	0.6200
0	1	0	0	1	1	0	26	0.6300
0	1	0	0	1	1	1	27	0.6400
0	1	0	1	0	0	0	28	0.6500
0	1	0	1	0	0	1	29	0.6600
0	1	0	1	0	1	0	2A	0.6700
0	1	0	1	0	1	1	2B	0.6800
0	1	0	1	1	0	0	2C	0.6900
0	1	0	1	1	0	1	2D	0.7000
0	1	0	1	1	1	0	2E	0.7100
0	1	0	1	1	1	1	2F	0.7200
0	1	1	0	0	0	0	30	0.7300
0	1	1	0	0	0	1	31	0.7400
0	1	1	0	0	1	0	32	0.7500
0	1	1	0	0	1	1	33	0.7600
0	1	1	0	1	0	0	34	0.7700
0	1	1	0	1	0	1	35	0.7800
0	1	1	0	1	1	0	36	0.7900
0	1	1	0	1	1	1	37	0.8000
0	1	1	1	0	0	0	38	0.8100
0	1	1	1	0	0	1	39	0.8200
0	1	1	1	0	1	0	3A	0.8300
0	1	1	1	0	1	1	3B	0.8400
0	1	1	1	1	0	0	3C	0.8500
0	1	1	1	1	0	1	3D	0.8600
0	1	1	1	1	1	0	3E	0.8700
0	1	1	1	1	1	1	3F	0.8800
1	0	0	0	0	0	0	40	0.8900

Table 1. TPS53632G VID Table (continued)

VID6	VID5	VID4	VID3	VID2	VID1	VID0	HEX	VOLTAGE
1	0	0	0	0	0	1	41	0.9000
1	0	0	0	0	1	0	42	0.9100
1	0	0	0	0	1	1	43	0.9200
1	0	0	0	1	0	0	44	0.9300
1	0	0	0	1	0	1	45	0.9400
1	0	0	0	1	1	0	46	0.9500
1	0	0	0	1	1	1	47	0.9600
1	0	0	1	0	0	0	48	0.9700
1	0	0	1	0	0	1	49	0.9800
1	0	0	1	0	1	0	4A	0.9900
1	0	0	1	0	1	1	4B	1.0000
1	0	0	1	1	0	0	4C	1.0100
1	0	0	1	1	0	1	4D	1.0200
1	0	0	1	1	1	0	4E	1.0300
1	0	0	1	1	1	1	4F	1.0400
1	0	1	0	0	0	0	50	1.0500
1	0	1	0	0	0	1	51	1.0600
1	0	1	0	0	1	0	52	1.0700
1	0	1	0	0	1	1	53	1.0800
1	0	1	0	1	0	0	54	1.0900
1	0	1	0	1	0	1	55	1.1000
1	0	1	0	1	1	0	56	1.1100
1	0	1	0	1	1	1	57	1.1200
1	0	1	1	0	0	0	58	1.1300
1	0	1	1	0	0	1	59	1.1400
1	0	1	1	0	1	0	5A	1.1500
1	0	1	1	0	1	1	5B	1.1600
1	0	1	1	1	0	0	5C	1.1700
1	0	1	1	1	0	1	5D	1.1800
1	0	1	1	1	1	0	5E	1.1900
1	0	1	1	1	1	1	5F	1.2000
1	1	0	0	0	0	0	60	1.2100
1	1	0	0	0	0	1	61	1.2200
1	1	0	0	0	1	0	62	1.2300
1	1	0	0	0	1	1	63	1.2400
1	1	0	0	1	0	0	64	1.2500
1	1	0	0	1	0	1	65	1.2600
1	1	0	0	1	1	0	66	1.2700
1	1	0	0	1	1	1	67	1.2800
1	1	0	1	0	0	0	68	1.2900
1	1	0	1	0	0	1	69	1.3000
1	1	0	1	0	1	0	6A	1.3100
1	1	0	1	0	1	1	6B	1.3200
1	1	0	1	1	0	0	6C	1.3300
1	1	0	1	1	0	1	6D	1.3400
1	1	0	1	1	1	0	6E	1.3500
1	1	0	1	1	1	1	6F	1.3600

Table 1. TPS53632G VID Table (continued)

VID6	VID5	VID4	VID3	VID2	VID1	VID0	HEX	VOLTAGE
1	1	1	0	0	0	0	70	1.3700
1	1	1	0	0	0	1	71	1.3800
1	1	1	0	0	1	0	72	1.3900
1	1	1	0	0	1	1	73	1.4000
1	1	1	0	1	0	0	74	1.4100
1	1	1	0	1	0	1	75	1.4200
1	1	1	0	1	1	0	76	1.4300
1	1	1	0	1	1	1	77	1.4400
1	1	1	1	0	0	0	78	1.4500
1	1	1	1	0	0	1	79	1.4600
1	1	1	1	0	1	0	7A	1.4700
1	1	1	1	0	1	1	7B	1.4800
1	1	1	1	1	0	0	7C	1.4900
1	1	1	1	1	0	1	7D	1.5000
1	1	1	1	1	1	0	7E	1.5100
1	1	1	1	1	1	1	7F	1.5200

7.4 Device Functional Modes

7.4.1 PWM Operation

The [Functional Block Diagram](#) and [Figure 12](#) show how the converter operates in continuous conduction mode (CCM).

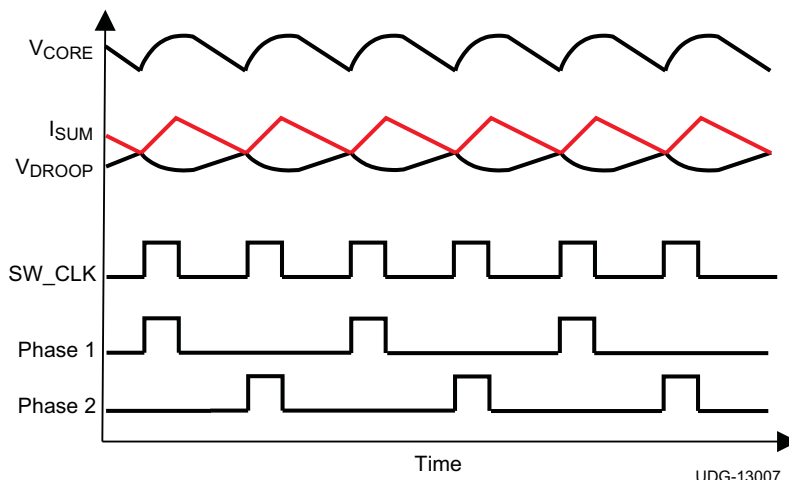


Figure 12. D-CAP+™ Mode Basic Waveforms

Starting with the condition that the high-side FETs are off and the low-side FETs are on, the summed current feedback (I_{SUM}) is higher than the error amplifier output (V_{COMP}). I_{CMP} falls until it hits V_{COMP} , which contains a component of the output ripple voltage. The PWM comparator senses where the two waveforms cross and triggers the on-time generator, which generates the internal SW_CLK signal. Each SW_CLK signal corresponds to one switching ON pulse for one phase.

During single-phase operation, every SW_CLK signal generates a switching pulse on the same phase. Also, I_{SUM} voltage corresponds to a single-phase inductor current only.

During multi-phase operation, the controller distributes the SW_CLK signal to each of the phases in a cycle. Using the summed inductor current and cyclically distributing the ON pulses to each phase automatically gives the required interleaving of $360/n$, where n is the number of phases.

7.5 Configuration and Programming

After the 5-V, 3.3-V, or V_{INTF} power is applied to the controller (all are above UVLO level), the following information is latched and cannot be changed anytime during operation. The [Electrical Characteristics](#) table defines the values of the selections.

7.5.1 Operating Frequency

The resistor between the FREQ-P pin and GND sets the switching frequency. See the [Electrical Characteristics](#) table for the resistor settings corresponding to each frequency selection.

NOTE

The operating frequency is a quasi-fixed frequency in the sense that the ON time is fixed based on the input voltage (at the VIN pin) and output voltage (set by VID). The OFF time varies based on various factors such as load and power-stage components.

7.5.2 Overcurrent Protection (OCP) Level

The resistor from OCP-I to GND sets the OCP level of the CPU channel. See the [Electrical Characteristics](#) table for the resistor settings corresponding to each OCP level.

Configuration and Programming (continued)

7.5.3 IMON Gain

The resistors from IMON to OCP-I and OCP-I to GND set the DC load current monitor (IMON) gain.

7.5.4 Slew Rate

The SetVID fast slew rate is set by the resistor from SLEWA pin to GND. See the [Electrical Characteristics](#) table for the resistor settings corresponding to each slew rate setting.

7.5.5 Base Address

The voltage on SLEWA pin sets the device base address.

7.5.6 Ramp Selection

The resistor from RAMP to GND sets the ramp compensation level. See the [Electrical Characteristics](#) table for the resistor settings corresponding to each ramp level.

7.5.7 Active Phases

Normally, the controller is configured to operate in 3-phase mode. To enable 2-phase mode, tie the CSP3 pin to a 3.3-V supply and the CSN3 pin to GND. To enable 1-phase mode, tie the CSP2 and CSP3 pins to a 3.3-V supply and tie the CSN2 and CSN3 pins to GND.

7.6 Register Maps

The I²C interface can support 400-kHz, 1-MHz, and 3.4-MHz clock frequencies. The I²C interface is accessible even when EN is low. The following registers are accessible via I²C.

7.6.1 Voltage Select Register (VSR) (00h)

- Type: Read and write
- Power-up value: 48h. This value can be changed before the rising edge of EN to change BOOT voltage.
- EN rising (after power-up): prior programmed value
- See [Table 1](#) for exact values
- A command to set VSR < 19h (minimum VID) generates a NAK and the VSR remains at the prior value

b7	b6	b5	b4	b3	b2	b1	b0
–	VID[6:0]						

7.6.2 IMON Register (03h)

- Type: Read only
- Power-up value: 00h
- EN rising (after power-up): 00h

b7	b6	b5	b4	b3	b2	b1	b0
MSB	–	–	–	–	–	–	LSB

7.6.3 VMAX Register (04h)

- Type: Read / write (see below)
- Power-up value: 1.28 V (OTP value)
- EN rising (after power-up): Last written value

b7	b6	b5	b4	b3	b2	b1	b0
Lock	MSB	–	–	–	–	–	LSB

Bit definitions:

BIT	NAME	DEFINITION
0 - 6	VMAX	Maximum VID setting
7	Lock	Access protection of the VMAX register 0: No protection, R/W access to bits 0-6 1: Access is read only; reset after UVLO event.

7.6.4 Power State Register (06h)

- Type: Read and write
- Power-up value: 00h
- EN rising (after power-up): 00h

b7	b6	b5	b4	b3	b2	b1	b0
–	–	–	–	–	–	MSB	LSB

Bit definitions:

VALUE	DEFINITION
0	Multi-phase CCM
1	Single-phase CCM
2	Single-phase DCM

7.6.5 SLEW Register (07h)

- Type: Read and write (see below)
- Power-up value: Defined by SLEWA pin at power-up
- EN rising (after power-up): Last written value
- Write only a single '1' for the SLEW rate desired

b7	b6	b5	b4	b3	b2	b1	b0
48 mV/μs	42mV/μs	36 mV/μs	30 mV/μs	24 mV/μs	18 mV/μs	12 mV/μs	6 mV/μs

7.6.6 Lot Code Registers (10-13h)

- Type: 8-bits; read only
- Power-up value: Programmed at factory

7.6.7 Fault Register (14h)

- Type: 8-bits; read only
- Power-up value: 00h

b7	b6	b5	b4	b3	b2	b1	b0
–	–	–	–	Device thermal shutdown	OVP	UVP	OCP

8 Applications and Implementation

8.1 Application Information

The TPS53632G device has a very simple design procedure. A Microsoft Excel[®]-based component value calculation tool is available. Please contact your local TI representative to get a copy of the spreadsheet.

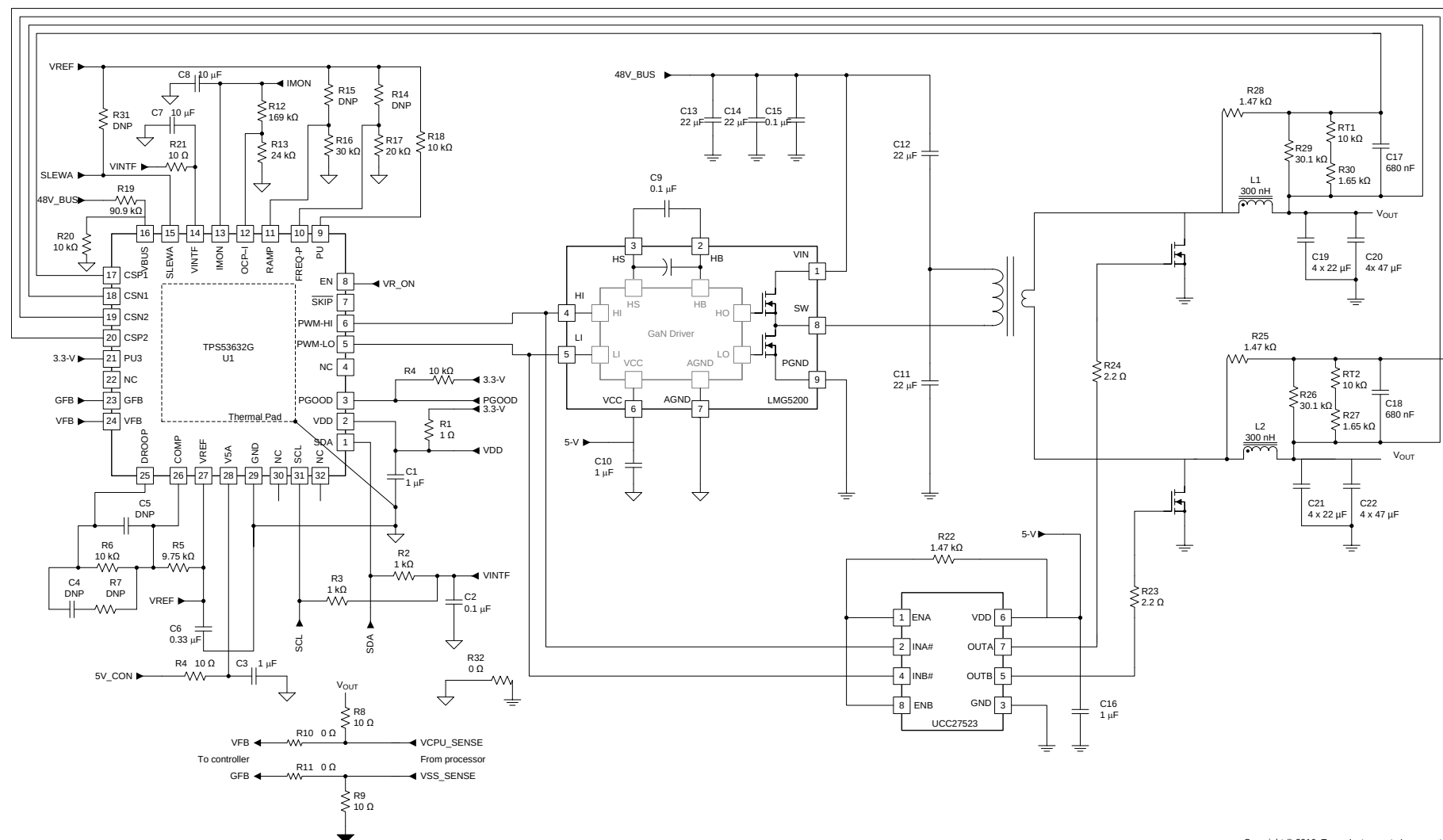
8.2 Typical Application

TPS53632G

SLUSJC3A – APRIL 2016 – REVISED JUNE 2016

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8.2.1 D-CAP+™ Half-Bridge Application



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Figure 13. Half-Bridge Application with GaN Power Stage on Primary Side

8.2.1.1 Design Requirements

Design example specifications:

- Input voltage range: 36 V to 72 V
- $V_{OUT} = 1.0\text{ V}$
- $I_{CC(max)} = 50\text{ A}$
- Slew rate (minimum): 12 mV/μs
- No Load Line

8.2.1.2 Detailed Design Procedure

8.2.1.2.1 Step 1: Select Switching Frequency

The switching frequency is selected by a resistor (R_F) between the FREQ_P pin and GND. The frequency is approximate and expected to vary based on load and input voltage.

Table 2. TPS53632G Device Frequency Selection Table

SELECTION RESISTOR (R_F) VALUE (kΩ)	OPERATING FREQUENCY (f_{sw}) (kHz)
20	300
24	400
30	500
39	600
56	700
75	800
100	900
150	1000

For this design, choose a switching frequency of 300 kHz. So, $R_F = 20\text{ kΩ}$.

8.2.1.2.2 Step 2: Set The Slew Rate

A resistor to GND (R_{SLEWA}) on SLEWA pin sets the slew rate. For a minimum 12 mV/μs slew rate, the resistor $R_{SLEWA} = 24\text{ kΩ}$.

Table 3. Slew Rate Versus Selection Resistor

SELECTION RESISTOR R_{SLEWA} (kΩ)	MINIMUM SLEW RATE (mV/μs)
20	6
24	12
30	18
39	24
56	30
75	36
100	42
150	48

NOTE

The voltage on the SLEWA pin also sets the base address. For a base address of 00, the SLEWA pin should have only one resistor, R_{SLEW} to GND. For other base addresses, a resistor can be connected between the SLEWA pin and the VREF pin (1.7 V). This resistor can be calculated to set the corresponding voltage for the required address listed in [Table 4](#).

Table 4. Address Selection

SLEWA VOLTAGE	BASE ADDRESS
$V_{SLEWA} \leq 0.30 \text{ V}$	0
$0.35 \text{ V} \leq V_{SLEWA} \leq 0.45 \text{ V}$	1
$0.55 \text{ V} \leq V_{SLEWA} \leq 0.65 \text{ V}$	2
$0.75 \text{ V} \leq V_{SLEWA} \leq 0.85 \text{ V}$	3
$0.95 \text{ V} \leq V_{SLEWA} \leq 1.05 \text{ V}$	4
$1.15 \text{ V} \leq V_{SLEWA} \leq 1.25 \text{ V}$	5
$1.35 \text{ V} \leq V_{SLEWA} \leq 1.45 \text{ V}$	6
$1.55 \text{ V} \leq V_{SLEWA} \leq 1.65 \text{ V}$	7

8.2.1.2.3 Step 3: Determine Inductor Value And Choose Inductor

Applications with smaller inductor values have better transient performance but also have higher voltage ripple and lower efficiency. Applications with higher inductor values have the opposite characteristics. It is common practice to limit the ripple current between 20% and 40% of the maximum current per phase. In this case, use 30%.

$$I_{P-P} = \frac{80(A)}{3} \times 0.4 = 10.6 (A) \quad (2)$$

$$L = \frac{V \times dT}{I_{P-P}} \quad (3)$$

In this equation,

$$V = V_{IN(max)} - V_{OUT} = 13V \quad (4)$$

$$dT = \frac{V_{OUT}}{(f \times V_{IN(max)})} = 238ns \quad (5)$$

So, calculating, $L = 0.29 \mu H$.

Choose an inductance value of $0.3 \mu H$. The inductor must not saturate during peak loading conditions.

$$I_{SAT} = \left(\frac{I_{CC(max)}}{n} + \frac{I_{P-P}}{2} \right) \times 1.2 = 38.4 A$$

where

- n is the number of phases (6)

The factor of 1.2 allows for current sensing and current limiting tolerances.

The chosen inductor should have the following characteristics:

- As flat as an inductance versus current curve as possible. Inductor DCR sensing is based on the idea L / DCR is approximately a constant through the current range of interest
- Either high saturation or soft saturation
- Low DCR for improved efficiency, but at least $0.6 m\Omega$ for proper signal levels
- DCR tolerance as low as possible for load-line accuracy

For this application, choose a $0.3\text{-}\mu H$, $0.29\text{-}m\Omega$ inductor.

8.2.1.2.4 Step 4: Determine Current Sensing Method

The TPS53632G device supports both resistor sensing and inductor DCR sensing. Inductor DCR sensing is chosen. For resistor sensing, substitute the resistor value for $R_{CS(eff)}$ in the subsequent equations.

8.2.1.2.5 Step 5: DCR Current Sensing

Design the thermal compensation network and selection of OCP. In most designs, NTC thermistors are used to compensate thermal variations in the resistance of the inductor winding. This winding is generally copper, and so has a resistance coefficient of 3900 PPM/°C. NTC thermistors, as an alternative, have very non-linear characteristics and need two or three resistors to linearize them over the range of interest. A typical DCR circuit is shown in [Figure 14](#).

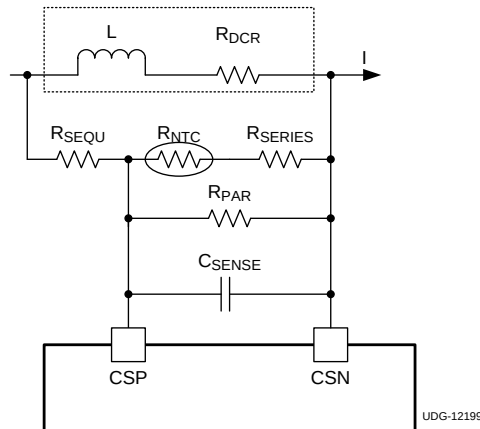


Figure 14. Typical DCR Sensing Circuit

In this design example, the voltage across the C_{SENSE} capacitor exactly equals the voltage across R_{DCR} when:

$$\frac{L}{R_{DCR}} - C_{SENSE} \times R_{EQ} \quad (7)$$

$$R_{EQ} = \left(\frac{R_{P_N} \times R_{SEQU}}{(R_{SEQU} + R_{P_N})} \right)$$

where

- R_{EQ} is the series (or parallel) combination of R_{SEQU} , R_{NTC} , R_{SERIES} and R_{PAR} (8)

$$R_{P_N} = \frac{R_{PAR} \times (R_{NTC} + R_{SERIES})}{R_{PAR} + R_{NTC} + R_{SERIES}} \quad (9)$$

Ensure that C_{SENSE} is a capacitor type which is stable over temperature. Use X7R or better dielectric (C0G preferred).

Because calculating these values by hand is difficult, TI offers a spreadsheet using the Excel solver function available to calculate them for you. Contact a TI representative to get a copy of the spreadsheet.

In this design, the following values are input to the spreadsheet.

- $L = 0.3 \mu H$
- $R_{DCR} = 0.29 m\Omega$
- Minimum Overcurrent Limit = 110 A
- Thermistor R25 = 10 k Ω and “B” value = 3380 k Ω

The spreadsheet then calculates the OCP setting and the values of R_{SEQU} , R_{SERIES} , R_{PAR} , and C_{SENSE} . In this case, the OCP setting is the value of the resistor that is connected between the OCP-I pin and GND. (100 k Ω) The nearest standard component values are:

- $R_{SEQU} = 1.47 k\Omega$
- $R_{SERIES} = 1.65 k\Omega$
- $R_{PAR} = 30.1 k\Omega$
- $C_{SENSE} = 680 nF$

Consider the effective divider ratio for the inductor DCR. Equation 10 shows the effective current sense resistance ($R_{CS(eff)}$) calculation.

$$R_{CS(eff)} = R_{DCR} \times \frac{R_{P_N}}{R_{SEQU} + R_{P_N}}$$

where

- R_{P_N} is the series and parallel combination of R_{NTC} , R_{SERIES} , and R_{PAR} (10)

$$R_{P_N} = \frac{R_{PAR} \times (R_{NTC} + R_{SERIES})}{R_{PAR} + R_{NTC} + R_{SERIES}}$$

where

- $R_{CS(eff)}$ is 0.244 mΩ (11)

8.2.1.2.6 Step 6: Select OCP Level

Set the OCP threshold level that corresponds to Equation 12.

$$I_{VALLEY} \times R_{CS(eff)} = V_{CS(ocp)} \quad (12)$$

$$I_{VALLEY} = \frac{I_{OCP}}{N_{PH}} - 0.5 - I_{RIPPLE} \quad (13)$$

Table 5. OCP Selection⁽¹⁾

SELECTION RESISTOR R_{OCP} (kΩ)	TYPICAL $V_{CS(ocp)}$ (mV)
20	4
24	8
30	13
39	19
56	25
75	32
100	40
150	49

(1) If a corresponding match is not found, then select the next higher setting.

8.2.1.2.7 Step 7: Set the Load-Line Slope

The load-line slope is set by resistor, R_{DROOP} (between the DROOP pin and the COMP pin) and resistor R_{COMP} (between the COMP pin and the VREF pin). The gain of the DROOP amplifier (A_{DROOP}) is calculated in Equation 14.

$$A_{DROOP} = \left(1 + \left(\frac{R_{DROOP}}{R_{COMP}} \right) \right) = \left(\frac{(R_{CS(eff)} \times A_{CS})}{R_{LL}} \right) = \frac{0.244 \text{ m} \times 6}{1.0 \text{ m}} = 1.46 \quad (14)$$

Set the value of R_{DROOP} to 10 kΩ, R_{COMP} as shown in Equation 15.

$$R_{COMP} = \frac{R_{DROOP}}{(A_{DROOP} - 1)} = 21.5 \text{ k} \Omega \quad (15)$$

Based on measurement, this value is adjusted to 9.75 kΩ.

NOTE

See [Loop Compensation for Zero Load-Line](#) for zero-load line.

8.2.1.2.8 Step 8: Current Monitor (IMON) Setting

Set the analog current monitor so that at $I_{CC(max)}$ the IMON pin voltage is 1.7 V. This corresponds to a digital I_{OUT} value of 'FF' in I²C register 03H. The voltage on the IMON pin is shown in [Equation 16](#).

$$V_{IMON} = 10 \times 1 + \frac{(R_{IMON})}{(R_{OCP})} \times \sum V_{CSn} \xrightarrow{\text{yields}} V \quad (16)$$

So,

$$1.7 = 10 \times \left(1 + \frac{R_{IMON}}{R_{OCP}} \right) \times R_{CS(eff)} \times I_{CC(max)}$$

where

- $I_{CC(max)}$ is 80 A
- $R_{CS(eff)}$ is 0.244 mΩ
- R_{OCP} is 24 kΩ

(17)

Solving, $R_{IMON} = 169 \text{ k}\Omega$. R_{IMON} is connected from IMON pin to OCP-I pin.

8.2.1.3 Application Performance Plots

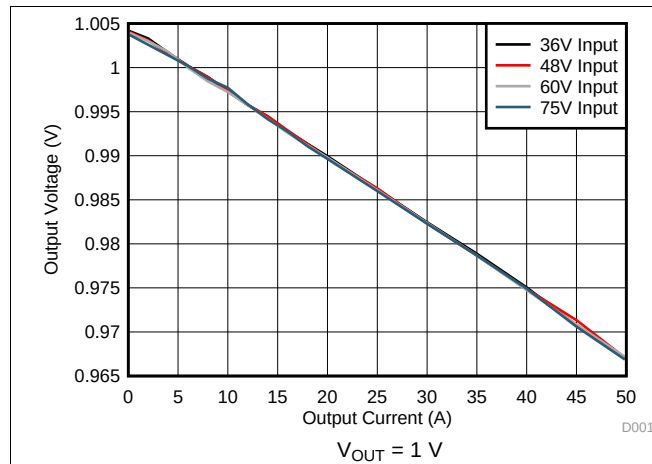


Figure 15. Output Voltage vs Output Current

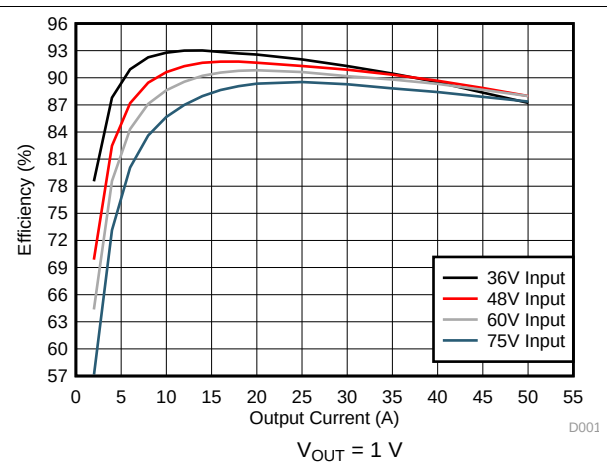


Figure 16. Efficiency vs Output Current

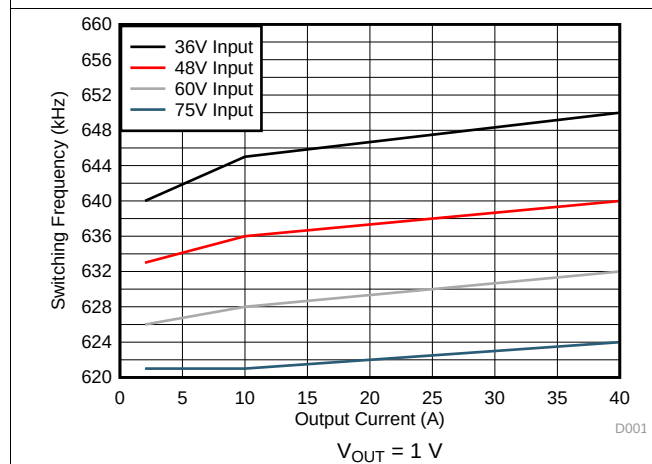


Figure 17. Switching Frequency vs Output Current

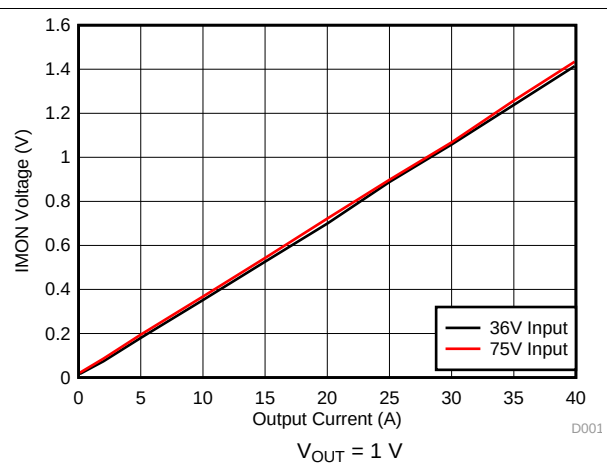


Figure 18. IMON Voltage vs Output Current

8.2.1.4 Loop Compensation for Zero Load-Line

The TPS53632G device control architecture (current mode, constant on-time) has been analyzed by the Center for Power Electronics Systems (CPES) at Virginia Polytechnic and State University. The following equations are from the presentation: *Equivalent Circuit Representation of Current-Mode Control* from November 21, 2008.

A simplified control loop diagram is shown in Figure 19. One of the benefits of this technology is the lack of the sample and hold effect that limits the bandwidth of fixed frequency current mode controllers and causes sub-harmonic oscillations.

The open loop gain, G_{OL} , is the gain of the error amplifier, multiplied by the control-to-output gain and is calculated in Equation 18.

$$G_{OL} = G_{COMP} \times G_{CO} \quad (18)$$

The control-to-output gain circuitry is shown in Figure 19.

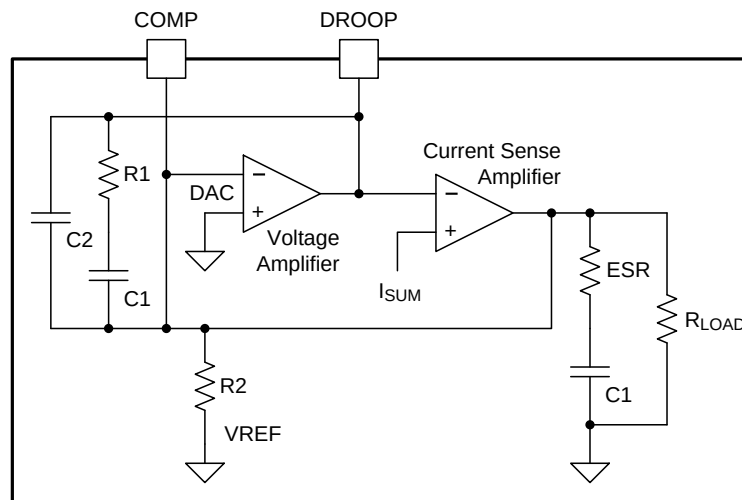


Figure 19. Control To Output Gain Circuitry

The control-to-output gain is calculated in Equation 19.

$$\frac{V_O}{V_C} = K_C \times \frac{1}{1 + \left(\frac{\omega}{Q_1 \times \omega_1} \right) + \left(\frac{\omega^2}{\omega_1^2} \right)} \times \frac{(\omega \times R_{ESR} \times C_{OUT}) + 1}{\left(\frac{\omega}{\omega_a} \right) + 1}$$

where

$$K_C = \frac{\left(\frac{R_{LOAD}}{R_i} \right)}{1 + \left(\frac{t_{ON} \times R_{LOAD}}{2 \times L_S} \right)}$$

- $\omega_1 = \frac{\pi}{t_{ON}}$
- $Q_1 = \frac{2}{\pi}$
- $t_{ON} = \frac{V_{OUT}}{V_{IN} \times f_{SW}}$

$$\omega_a = \frac{1 + \left(\frac{t_{ON} \times R_{LOAD}}{2 \times L_S} \right)}{R_{LOAD} \times C_{OUT} \times \left(1 + \left(\frac{t_{ON} \times R_{LOAD}}{2 \times L_S} \right) \right)} \quad (19)$$

For this converter, $R_i = R_{CS(eff)} \times A_{CS}$

The theoretical control-to-output transfer function shows 0-dB bandwidth is approximately 20 kHz and the phase margin is greater than 90°. As a result, creating the desired loop response is a matter of adding an appropriate pole-zero or pole-zero-pole compensation for the high-gain system.

The loop compensation is designed to meet the following criteria:

1. Phase margin $\geq 60^\circ$
 - (a) More stable and settles more quickly for repetitive transients
2. Bandwidth: $\frac{f_{SW}}{5} \geq BW \geq \frac{f_{SW}}{3}$
 - (a) High-enough BW for good transient response.
 - (b) If too high, the response for the voltage changes gets very “bumpy”, as each voltage step causes several pulses very quickly.
3. The phase angle of the compensation at the switching frequency needs to be very near to 0 degrees (resistive)
 - (a) Otherwise, there is a phase shift between DROOP and ISUM
 - (b) Practically, this means the zero frequency should be $< f_{SW} / 2$, and any high-frequency pole (for noise rejection) needs to be $> 2 \times f_{SW}$.

The voltage error amplifier is used in the design. The compensation technique used here is a type II compensator. Equation 20 describes the transfer function, which has a pole that occurs at the origin. The type II amplifier also has a 0 (f_z) that can be programmed by selecting R1 and C1 values. In addition, the type II compensation network has a pole (f_p) that can be programmed by selecting R1 and C2.

$$G_{COMP} = \frac{1}{s \times (C1 + C2) \times R2} \times \frac{(s \times R1 \times C1 + 1)}{s \times R1 \times \left(\frac{C1 \times C2}{C1 + C2} \right) + 1} \quad (20)$$

$$f_z = \frac{1}{2\pi \times R1 \times C1} \quad (21)$$

$$f_p = \frac{1}{2\pi \times R1 \times \left(\frac{C1 \times C2}{C1 + C2} \right)} \quad (22)$$

R1 sets the loop crossover to correct for the gain at control to output function. In this design, select $R2 = 2 \text{ k}\Omega$.

$$R1 = R2 \times 10^{\left(\frac{-G_{CO(fc)}}{20} \right)} = 2 \text{ k}\Omega \times 10^{\left(\frac{-10 \text{ dB}}{20} \right)} \quad (23)$$

Capacitor C1 adds phase margin at crossover frequency and can be set between 10% and 20% of the switching frequency.

$$C1 = \frac{1}{2\pi \times f_{SW} \times 0.1 \times R1} \quad (24)$$

The last consideration for the voltage loop compensation design is C2. The purpose of C2 is to cancel the phase gain caused by the ESR of the output capacitor in the control-to-output function after the loop crossover. To ensure the gain continues to roll off after the voltage loop crossover, the C2 is selected to meet Equation 25.

$$C2 = \frac{C_{OUT} \times \text{ESR}}{R1} \quad (25)$$

9 Power Supply Recommendations

This device is designed to operate from a supply voltage at the V5A pin (5-V power input for analog circuits) from 4.5 V to 5.5 V and a supply voltage at the VDD pin (3.3-V digital power input) from 3.1 V to 3.5 V, and a supply voltage at the VINTF pin from 1.7 V to 3.5 V. Use only a well-regulated supply. The VIN pin input must be connected to the conversion input voltage and must not exceed 28 V. Proper bypassing of the V5A and VDD input supplies is critical for noise performance, as is PCB layout and grounding scheme. See the recommendations in the [Layout](#) section.

10 Layout

10.1 Layout Guidelines

10.1.1 PCB Layout

- Check the pinout of the controller on schematic against the pinout of the datasheet.
- Have a component value calculator tool ready to check component values.
- Carefully check the choice of inductor and DCR.
- Carefully check the choice of output capacitors.
- Because the voltage and current feedback signals are fully differential, double check their polarity.
 - CSP1 / CSN1
 - CSP2 / CSN2
 - VOUT_SENSE to VFB / GND_SENSE to GFB
- Make sure the pull-up on the SDA, and SCL lines are correct. Ensure there is a bypass capacitor close to the device on the pull-up VINTF rail to GND of the device.
- TI strongly recommends that the device GND be separate from the system and Power GND.

Most Critical Layout Rule

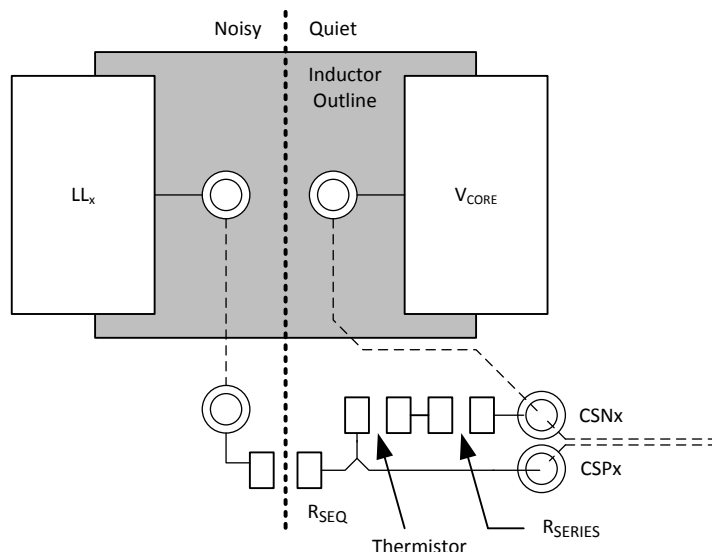
Make sure to separate noisy driver interface lines.

The driver is outside of the device. All gate-drive and switch-node traces must be local to the inductor and MOSFETs.

10.1.2 Current Sensing Lines

Given the physical layout of most systems, the current feedback (CSPx and CSNx) may have to pass near the power chain.

Layout Guidelines (continued)



UDG-12198

Figure 20. Kelvin Connections To The Inductor For DCR Sensing

Good load-line, current sharing, and current limiting performance of the TPS53632G device requires clean current feedback, so take the following precautions:

- Ensure all vias in the CSPx and CSNx traces are isolated from all other signals.
- TI recommends dotted signal traces be run in internal planes.
- If possible, change the name of the CSNx trace if possible to prevent automatic ties to the V_{CORE} plane.
- Put R_{SEQ} at the boundary between noisy and quiet areas.
- Run CSPx and CSNx as a differential pair in a quiet layer.
- Place the capacitor as near to the device pins as possible.
- Make a Kelvin connection to the pads of the resistor or inductor used for current sensing. See Figure 20 for a layout example.
- Run the current feedback signals as a differential pair to the device.
- Run the lines in a quiet layer. Isolate the lines from noisy signals by a voltage or ground plane.
- Put the compensation capacitor for DCR sensing (C_{SENSE}) as close to the CS pins as possible.
- Place any noise filtering capacitors directly under or near the TPS53632G device and connect to the CS pins with the shortest trace length possible.

10.1.3 Feedback Voltage Sensing Lines

The voltage feedback coming from the CPU socket must be routed as a differential pair all the way to the VFB and GFB pins of the TPS53632G device. Avoid routing over switch-node and gate-drive traces.

10.1.4 PWM And SKIP Lines

The PWM and SKIP lines should be routed from the TPS53632G device to the driver without crossing any switch-node or the gate drive signals.

10.1.4.1 Minimize High Current Loops

Figure 21 shows the primary current loops in each phase, numbered in order of importance.

Layout Guidelines (continued)

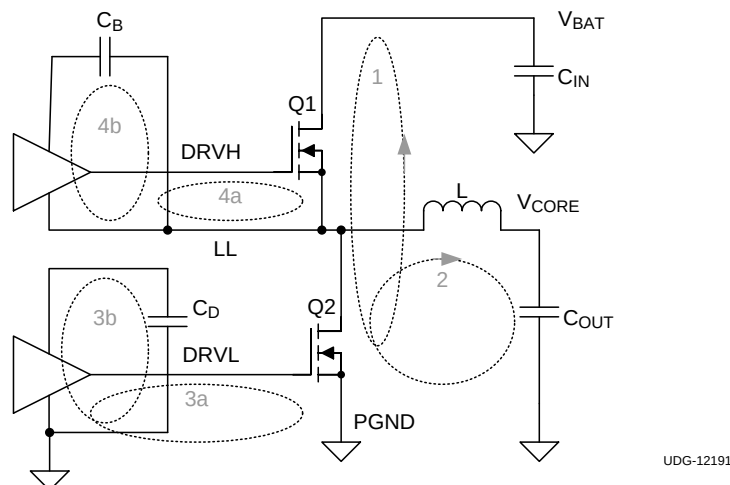


Figure 21. Major Current Loops To Minimize

The most important loop to minimize the area of is loop 1, the path from the input capacitor through the high and low-side FETs, and back to the capacitor through ground.

Loop 2 is from the inductor through the output capacitor, ground, and Q2. The layout of the low-side gate drive (Loops 3a and 3b) is important. The guidelines for the gate drive layout are:

- Make the low-side gate drive as short as possible (1 in or less preferred).
- Make the DRV_L width to length ratio of 1:10, wider (1:5) if possible.
- If changing layers is necessary, use at least two vias.

10.1.5 Power Chain Symmetry

The TPS53632G device does not require special care in the layout of the power chain components because independent isolated current feedback is provided. Lay out the phases in a symmetrical manner, if possible. The rule is: the current feedback from each phase needs to be clean of noise and have the same effective current-sense resistance.

10.1.6 Component Location

Place components as close to the device in the following order.

1. CS pin noise filtering components
2. COMP pin and DROOP pin compensation components
3. Decoupling capacitors for VREF, VDD, V5A, and VINTF
4. Decoupling capacitor for VINTF rail, which is pullup voltage for the digital lines. This decoupling should be placed near the device to have good signal integrity.
5. OCP-I resistors, FREQ_P resistors, SLEWA resistors, and RAMP resistors

10.1.7 Grounding Recommendations

The TPS53632G device has an analog ground and a thermal pad. The usual procedure for connecting these is:

- Keep the analog GND of the device and the power GND of the power circuit separate. The device analog GND and the power circuit power GND can be connected at one single quiet point in the layout.
- The thermal pad does not have an electrical connection to device. But the thermal pad must be connected to GND pin (pin 29) of the device to give good ground shielding. Do not connect the thermal pad to system GND.
- Tie the thermal pad to a ground island with at least 4 vias. All the analog components can connect to this analog ground island.
- The analog ground can be connected to any quiet spot on the system ground. A quiet spot is defined as a

Layout Guidelines (continued)

spot where no power supply switching currents are likely to flow. Use a single point connection from analog ground to the system ground.

- Ensure that the low-side MOSFET source connection and the input decoupling capacitors have a sufficient number of vias.

10.1.8 Decoupling Recommendations

- Decouple V5A and VDD to GND with a ceramic capacitor (with a value of at least 1 μF).
- Decouple VINTF to GND with a capacitor (with a value of at least 0.1 μF) to GND.

10.1.9 Conductor Widths

- Follow TI guidelines with respect to the voltage feedback and logic interface connection requirements.
- Maximize the widths of power, ground, and drive signal connections.
- For conductors in the power path, be sure there is adequate trace width for the amount of current flowing through the traces.
- Make sure there are sufficient vias for connections between layers. Use 1 via minimum per ampere of current.

10.2 Layout Example

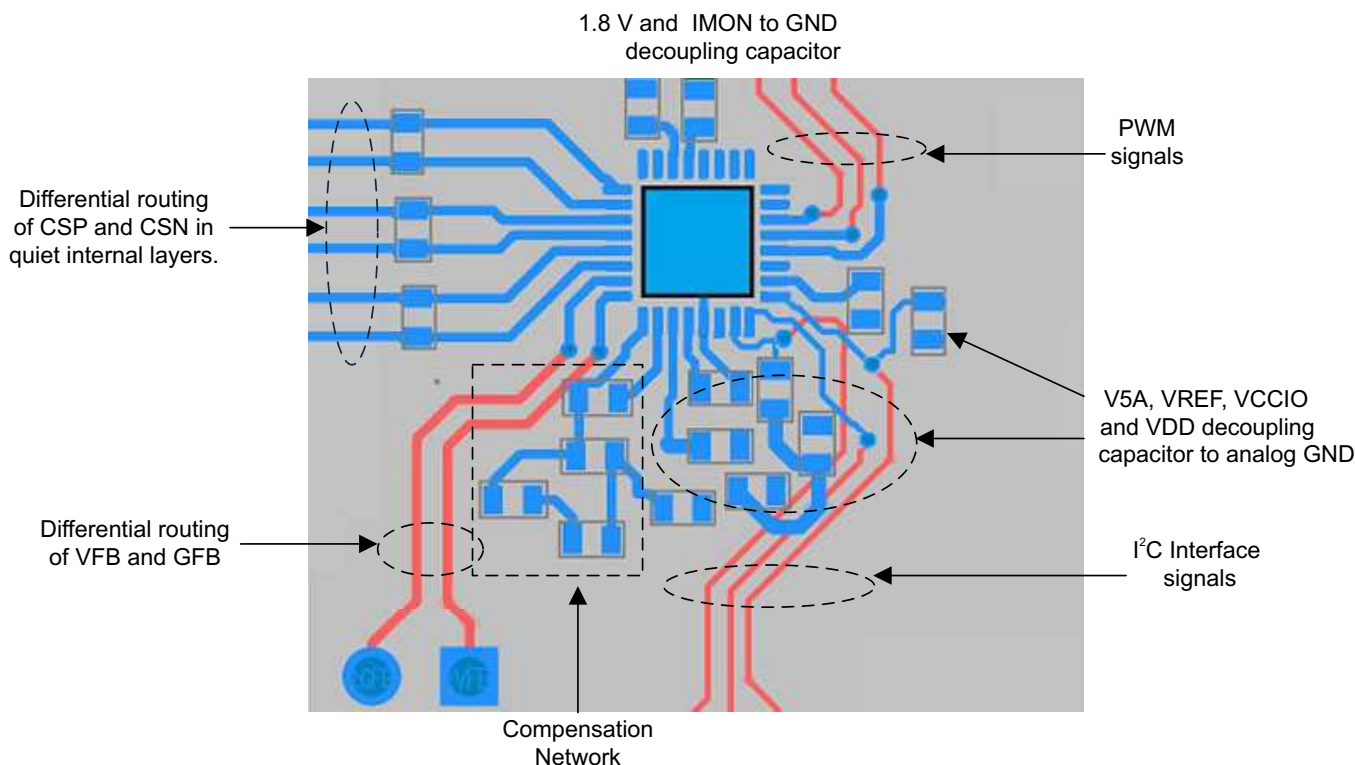


Figure 22. Example Layout

11 Device and Documentation Support

11.1 Trademarks

D-CAP+ is a trademark of Texas Instruments.

Excel is a registered trademark of Microsoft Corporation.

All other trademarks are the property of their respective owners.

11.2 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

11.3 Glossary

[SLYZ022](#) — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TPS53632GRSMR	ACTIVE	VQFN	RSM	32	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-10 to 105	TPS 53632G	Samples
TPS53632GRSMT	ACTIVE	VQFN	RSM	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-10 to 105	TPS 53632G	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

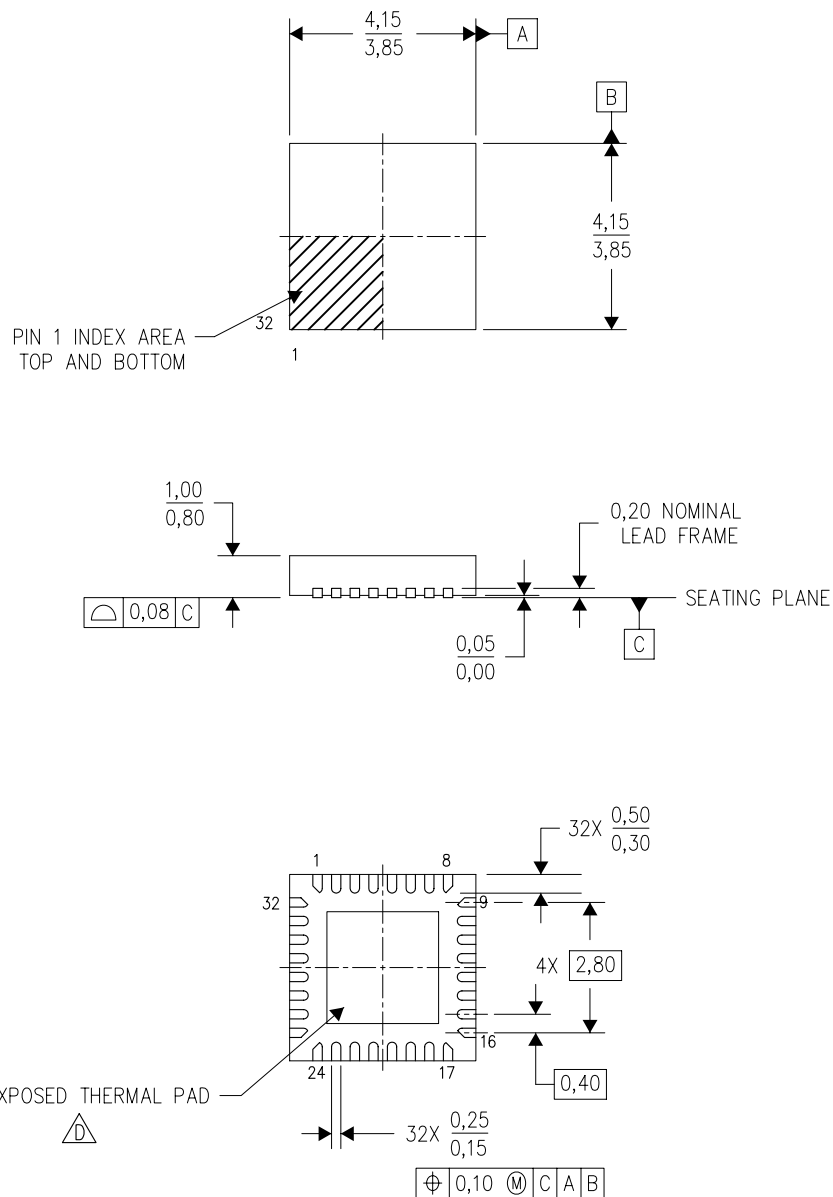
(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

RSM (S-PVQFN-N32)

PLASTIC QUAD FLATPACK NO-LEAD



4207560/B 03/10

- NOTES:
- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - B. This drawing is subject to change without notice.
 - C. QFN (Quad Flatpack No-Lead) Package configuration.
 -  D. The package thermal pad must be soldered to the board for thermal and mechanical performance. See the Product Data Sheet for details regarding the exposed thermal pad dimensions.

RSM (S-PVQFN-N32)

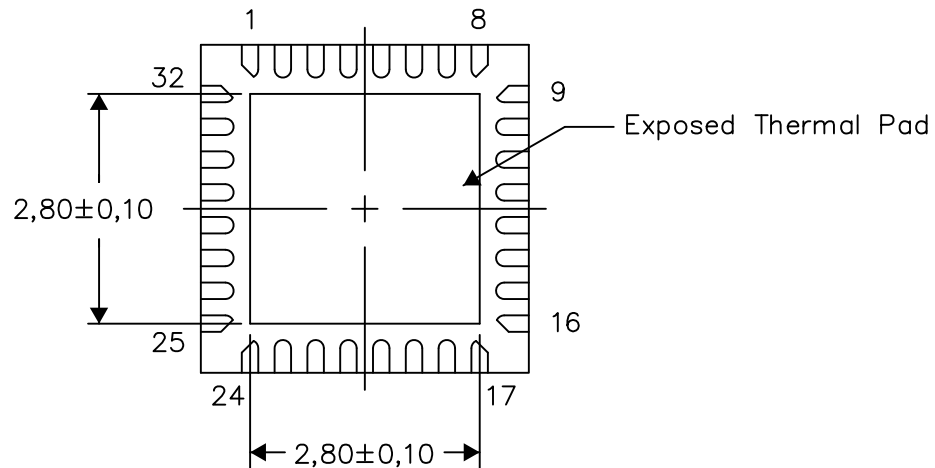
PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

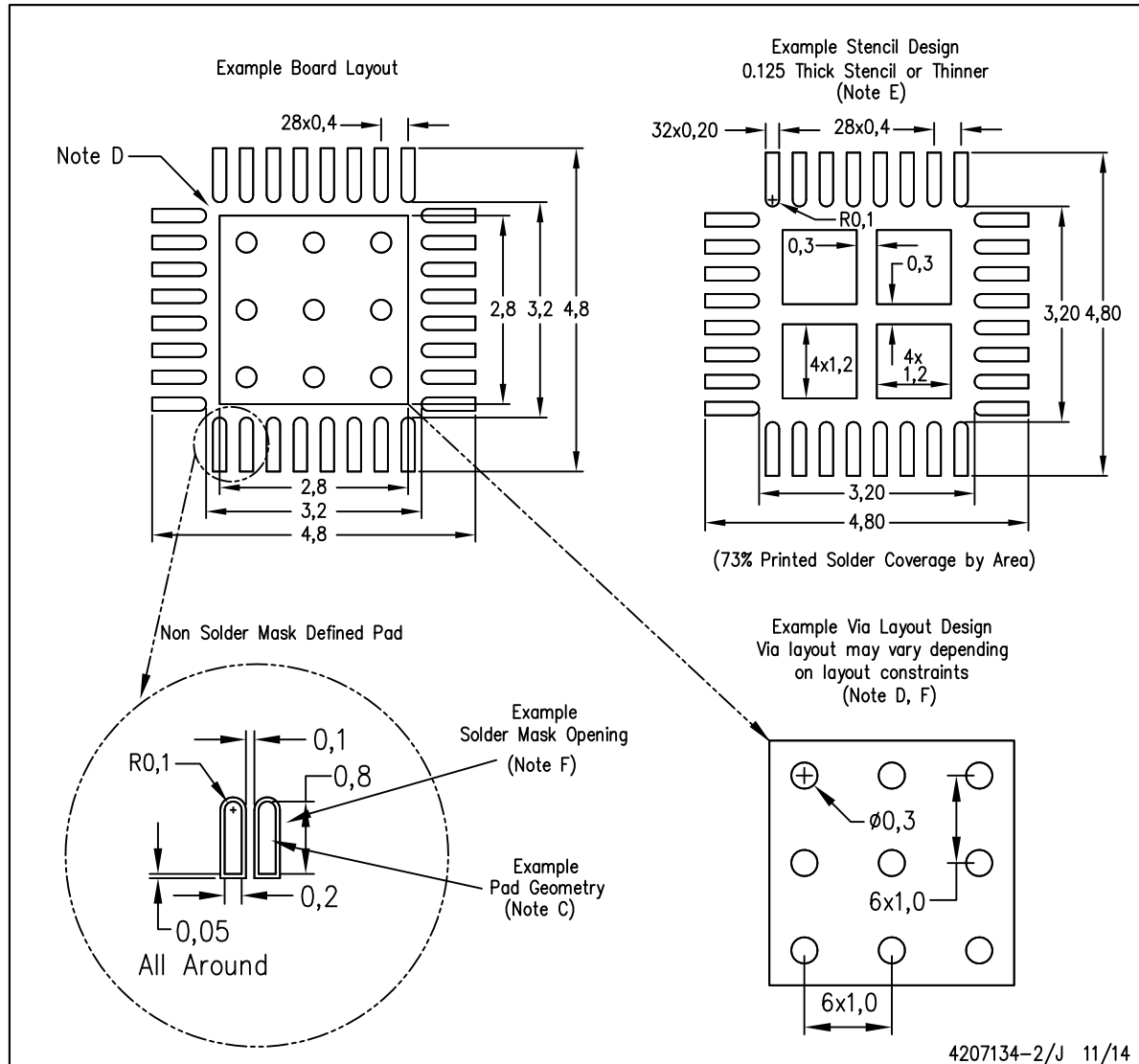
Exposed Thermal Pad Dimensions

4207868-2/1 07/14

NOTE: All linear dimensions are in millimeters

RSM (S-PVQFN-N32)

PLASTIC QUAD FLATPACK NO-LEAD



- NOTES:
- All linear dimensions are in millimeters.
 - This drawing is subject to change without notice.
 - Publication IPC-7351 is recommended for alternate designs.
 - This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <<http://www.ti.com>>.
 - Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
 - Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.

IMPORTANT NOTICE

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